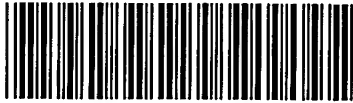


**Search Notes**

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Examiner

Ha T. Nguyen

Applicant(s)/Patent under  
Reexamination

NAKAMURA ET AL.

Art Unit

2812

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST search (see printout)	7/26/2005	hn